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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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Application of :
Tatsuya MIYATANI et al. :
Serial No. 09/966,719 : Group Art Unit - 2881
Filed: September 27, 2001 : Examiner - Phillip A. Johnston
For: SCANNING PROBE MICROSCOPE : Docket No. S004-4403

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COMMISSIONER OF PATENTS AND TRADEMARKS
Washington, DC 20231

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RESPONSE

S I R:

In response to the Office Action dated January 16, 2003, applicants amend their application as follows:

IN THE SPECIFICATION:

Replace the paragraph beginning at line 4 of page 1 with the following rewritten paragraph:

--Fig. 10 is an outline view of an atomic force microscope (AFM), which is one type of scanning probe microscope (SPM) of the related art. In Fig. 10, reference numeral 1001 is an XYZ translator, 1002 is a sample stage,

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